

ABSTRACT OF THE DISCLOSURE

A semiconductor testing apparatus includes
a test program memory for storing a test program,
a measuring/deciding section for receiving the test
program and supplying a test signal to the
semiconductor device with a wait time set to
a predetermined value and detecting an optimal value of
a wait time, after an elapse of the wait time, based
on a response signal outputted from the semiconductor
device and effecting an OK/NG decision on the
electrical characteristics of the semiconductor device
based on a result of the measurement and, if the result
of the decision is found to be "NG", remeasuring the
electrical characteristics of the semiconductor device
under a newly set wait time and effecting such
remeasurement on the electrical characteristics of the
semiconductor device at each newly set wait time until
the result of such decision becomes "OK".

卷之三